

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/597,376	AVIS, MARK	
Examiner	Art Unit	
 Brian Nash	3721	

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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